

Hierarchical identification of NBTI-critical gates in nanoscale logic

Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

Jenihhin, Maksim; Squillero, Giovanni; Tihomirov, Valentin; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <https://doi.org/10.1007/s10836-016-5589-x> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG

Palermo, N.; **Tihomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim; Raik, Jaan; Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102405>

Rejuvenation of NBTI-impacted processors using evolutionary generation of assembler programs

Pellerey, Francesco; **Jenihhin, Maksim**; Squillero, Giovanni; **Raik, Jaan**; Sonza Reorda, Matteo; **Tihomirov, Valentin; Ubar, Raimund-Johannes** 2016 IEEE 25th Asian Test Symposium : 21-24 November 2016, Hiroshima, Japan 2016 / p. 304-309 : ill <https://doi.org/10.1109/ATS.2016.57> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)